Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/669,177	SHEN ET AL.		
Examiner	Art Unit		
R. Stephen Dildine	2133		

SEARCHED				
Class	Subclass	Date	Examiner	
714	752, 791 and 794	5/2/2006	RSD	
Н03М	13/11	5/3/2006	RSD	
Н03М	13/13	5/3/2006	RSD	
нозм	13/39	5/3/2006	RSD	
Update	all above	8/29/2006	RSD	
Update	all above	1/24/2007	RSD	
		_		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	1		
	, see Search printout	8/29/2006	RSD

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB (see Search History printout)	5/3/2006	RSD
IEEEXplore	5/3/2006	RSD
Update all above	8/29/2006	RSD
Update all above	1/24/2007	RSD
-		
·		
Inventors' name search	5/3/2006	RSD